

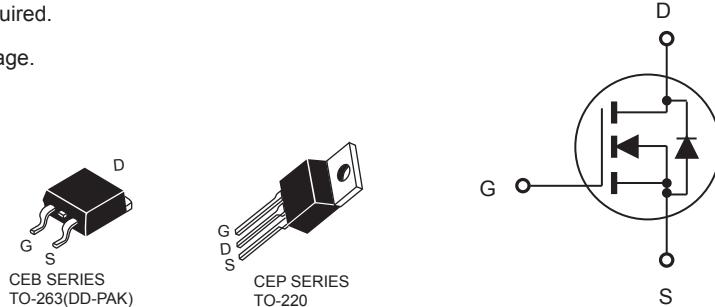


# CEP1012/CEB1012

## N-Channel Enhancement Mode Field Effect Transistor

### FEATURES

- 120V, 15A,  $R_{DS(ON)} = 120\text{m}\Omega$  @ $V_{GS} = 10\text{V}$ .
- Super high dense cell design for extremely low  $R_{DS(ON)}$ .
- High power and current handling capability.
- Lead free product is acquired.
- TO-220 & TO-263 package.



### ABSOLUTE MAXIMUM RATINGS $T_C = 25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Limit	Units
Drain-Source Voltage	$V_{DS}$	120	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Drain Current-Continuous	$I_D$	15	A
Drain Current-Pulsed <sup>a</sup>	$I_{DM}$	40	A
Maximum Power Dissipation @ $T_C = 25^\circ\text{C}$ - Derate above $25^\circ\text{C}$	$P_D$	100 0.8	W W/ $^\circ\text{C}$
Operating and Store Temperature Range	$T_J, T_{stg}$	-65 to 150	$^\circ\text{C}$

### Thermal Characteristics

Parameter	Symbol	Limit	Units
Thermal Resistance, Junction-to-Case	$R_{JC}$	1.25	$^\circ\text{C}/\text{W}$
Thermal Resistance, Junction-to-Ambient	$R_{JA}$	62.5	$^\circ\text{C}/\text{W}$



# CEP1012/CEB1012

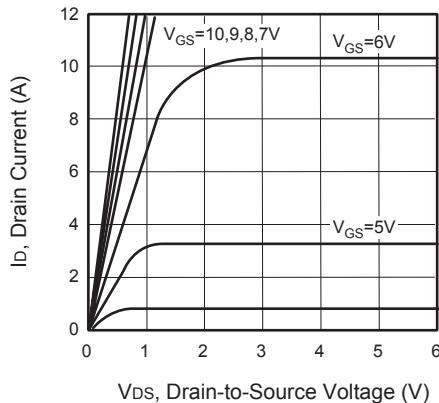
## Electrical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

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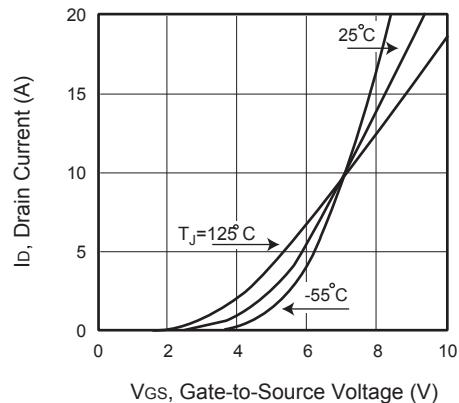
Parameter	Symbol	Test Condition	Min	Typ	Max	Units
<b>Off Characteristics</b>						
Drain-Source Breakdown Voltage	$\text{BV}_{\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	120			V
Zero Gate Voltage Drain Current	$I_{\text{DSS}}$	$V_{\text{DS}} = 120\text{V}, V_{\text{GS}} = 0\text{V}$			25	$\mu\text{A}$
Gate Body Leakage Current, Forward	$I_{\text{GSSF}}$	$V_{\text{GS}} = 20\text{V}, V_{\text{DS}} = 0\text{V}$			100	nA
Gate Body Leakage Current, Reverse	$I_{\text{GSSR}}$	$V_{\text{GS}} = -20\text{V}, V_{\text{DS}} = 0\text{V}$			-100	nA
<b>On Characteristics<sup>b</sup></b>						
Gate Threshold Voltage	$V_{\text{GS(th)}}$	$V_{\text{GS}} = V_{\text{DS}}, I_D = 250\mu\text{A}$	2		4	V
Static Drain-Source On-Resistance	$R_{\text{DS(on)}}$	$V_{\text{GS}} = 10\text{V}, I_D = 10\text{A}$		90	120	$\text{m}\Omega$
<b>Dynamic Characteristics<sup>c</sup></b>						
Forward Transconductance	$g_{\text{FS}}$	$V_{\text{DS}} = 10\text{V}, I_D = 5\text{A}$		6		S
Input Capacitance	$C_{\text{iss}}$	$V_{\text{DS}} = 25\text{V}, V_{\text{GS}} = 0\text{V}, f = 1.0 \text{ MHz}$		685		pF
Output Capacitance	$C_{\text{oss}}$			190		pF
Reverse Transfer Capacitance	$C_{\text{rss}}$			80		pF
<b>Switching Characteristics<sup>c</sup></b>						
Turn-On Delay Time	$t_{\text{d(on)}}$	$V_{\text{DD}} = 30\text{V}, I_D = 15\text{A}, V_{\text{GS}} = 10\text{V}, R_{\text{GEN}} = 20\Omega$		14	28	ns
Turn-On Rise Time	$t_r$			9	18	ns
Turn-Off Delay Time	$t_{\text{d(off)}}$			36	72	ns
Turn-Off Fall Time	$t_f$			14	28	ns
Total Gate Charge	$Q_g$	$V_{\text{DS}} = 96\text{V}, I_D = 10\text{A}, V_{\text{GS}} = 10\text{V}$		23.1	30.7	nC
Gate-Source Charge	$Q_{\text{gs}}$			3.6		nC
Gate-Drain Charge	$Q_{\text{gd}}$			8.9		nC
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
Drain-Source Diode Forward Current	$I_S$				10	A
Drain-Source Diode Forward Voltage <sup>b</sup>	$V_{\text{SD}}$	$V_{\text{GS}} = 0\text{V}, I_S = 10\text{A}$			1.2	V

## Notes :

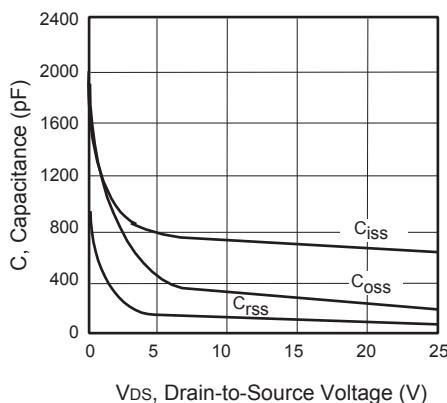
- a.Repetitive Rating : Pulse width limited by maximum junction temperature.
- b.Pulse Test : Pulse Width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 2\%$ .
- c.Guaranteed by design, not subject to production testing.



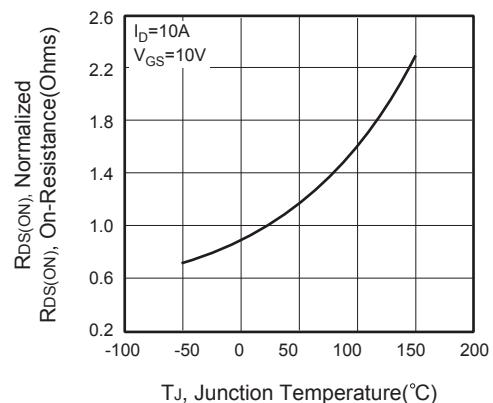
**Figure 1. Output Characteristics**



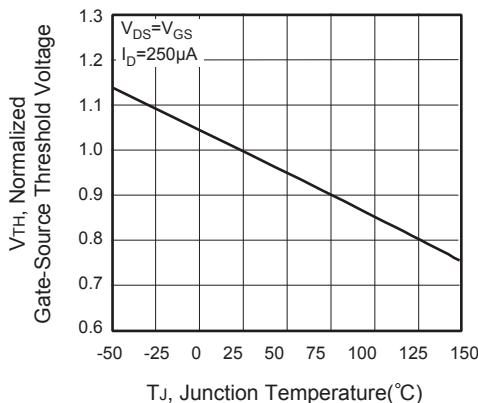
**Figure 2. Transfer Characteristics**



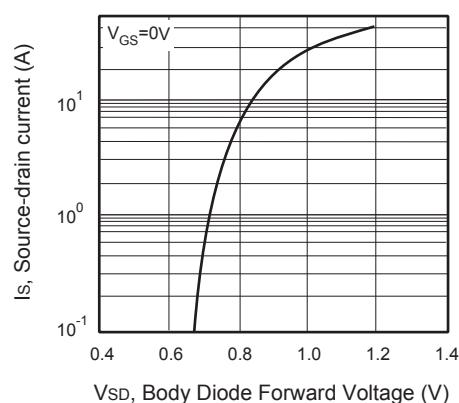
**Figure 3. Capacitance**



**Figure 4. On-Resistance Variation with Temperature**



**Figure 5. Gate Threshold Variation with Temperature**



**Figure 6. Body Diode Forward Voltage Variation with Source Current**

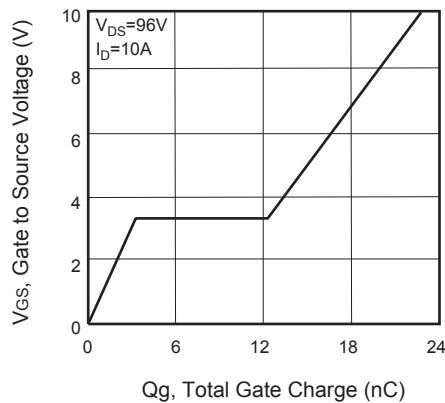


Figure 7. Gate Charge

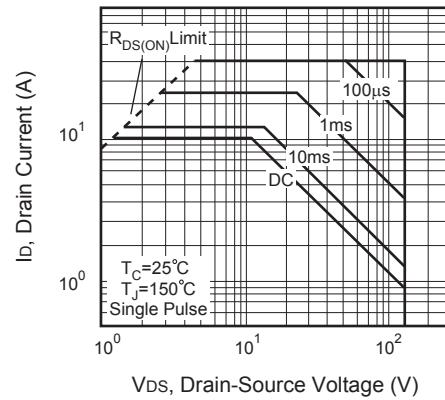


Figure 8. Maximum Safe Operating Area

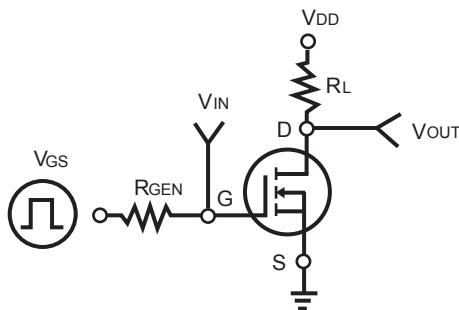


Figure 9. Switching Test Circuit

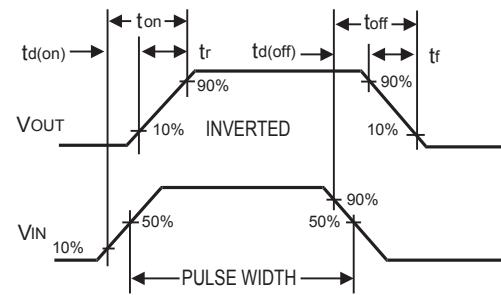


Figure 10. Switching Waveforms

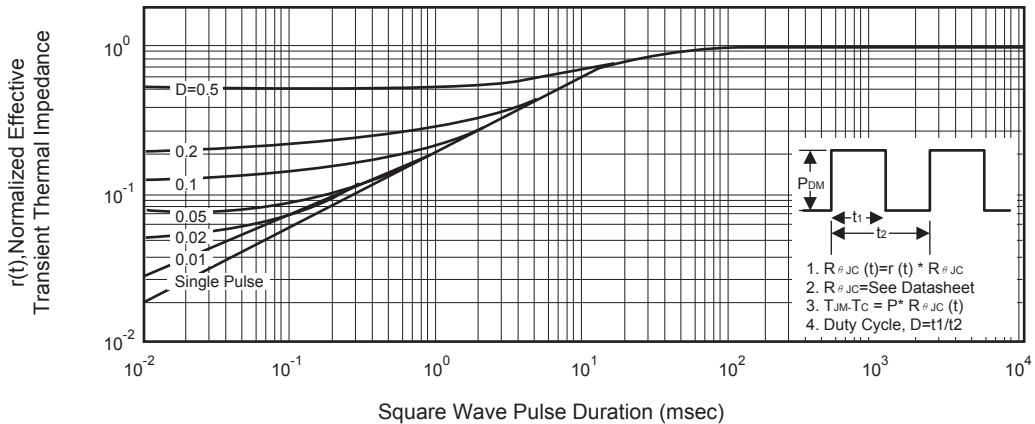


Figure 11. Normalized Thermal Transient Impedance Curve